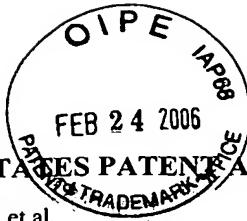


Docket No. 243190US2



IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Eiju KOMURO, et al.

SERIAL NO: 10/670,234

GAU: 2817

FILED: September 26, 2003

EXAMINER: TAKAOKA, DEAN O.

FOR: THIN-FILM PIEZOELECTRIC RESONATOR AND METHOD FOR FABRICATING THE SAME

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97(i)

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to have the references listed on the attached European Search Report and listed on form PTO-1449 placed in the file under 37 C.F.R. § 1.97(i). Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.

Gregory J. Maier

Registration No. 25,599

Customer Number

22850

Tel. (703) 413-3000
Fax. (703) 413-2220
(OSMMN 05/03)
I:\ATTY\RAR\IDS\WORK\243190US_IDS.DOC

Ronald A. Rudder, Ph.D.
Registration No. 45,618

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 243190US2		SERIAL NO. 10/670,234	
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 1px solid black; border-radius: 50%; text-align: center; line-height: 100px; font-size: 24px; font-weight: bold;">O I P E</div> <div style="position: absolute; bottom: 0; left: 0; width: 100%; height: 100%; border: 1px solid black; border-radius: 50%; text-align: center; line-height: 100px; font-size: 24px; font-weight: bold;">I A R P</div> <div style="position: absolute; top: 50%; left: 50%; transform: translate(-50%, -50%); font-size: 18px; font-weight: bold;">FEB 24 2006</div> <div style="position: absolute; top: 0; left: 50%; transform: translate(-50%, 0); font-size: 10px; font-weight: bold;">PATENT & TRADEMARK OFFICE</div> </div>				LIST OF REFERENCES CITED BY APPLICANT			
				APPLICANT Eiju KOMURO, et al.			
				FILING DATE September 26, 2003		GROUP 2817	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	US 2002/0190814	12/19/2002	Yamada et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	WO 02/45265	06/06/2002	WIPO			
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Su Q. X et al, "Edge Supported ZnO Thin Film Bulk Acoustic Wave Resonators and Filter Design", Frequency Control Symposium and Exhibition, 2000. Proceedings of the 2000 IEEE/EIA International 7-9 June 2000, USA, IEEE, 2000 pgs. 434-440					
	AX	Patent Abstract of Japan, 04046411, 02/17/1992, JAPAN					
	AY	Patent Abstract of Japan, 2001211052, 08/03/2001, JAPAN					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							